Calculating Tracker parameters

In view of upgrades to tracker, how much of performance can be estimated without running very lengthy simulations?

Quantities of interest: angular and momentum resolution, impact parameter resolution

Variables: no layers, locations, spatial resolution, material budget

Impact Parameter estimation



- IP determined by projection to beam from first measurement plane, R_1
 - including bending and multiple scattering at beam pipe

$$\sigma_{IP}^2 \approx \sigma_1^2 + R_0^2 \sigma_0^2(\theta_{MS}) + R_1^2 \sigma^2(\theta) + 0.25 R_1^4 \sigma^2(\rho) \qquad \rho = 1/R$$

- actually an approximation: should properly include correlations
- Wish to know
 - angular and momentum resolution: $\sigma(\theta)$, $\sigma(\rho)$ & multiple scattering errors
- Assumes (good approximations)
 - angles are small
 - high enough momentum for curvature ρ to be small: ~ 1 GeV/c

Impact Parameter calculation

• Linear least squares problem for straight line

$$\chi^2 = \sum_{i} \frac{(y_i - R_i \theta)^2}{\sigma_i^2}$$
 with $\frac{d\chi^2}{d\theta} = 0$ has solutions

$$\theta = \frac{\sum \frac{y_i R_{i1}}{\sigma_i^2}}{\sum \frac{R_{i1}^2}{\sigma_i^2}} \quad \sigma^2(\theta) = \frac{1}{\sum \frac{R_{i1}^2}{\sigma_i^2}} \quad R_{i1} = R_i - R_1$$

- More general problem of fitting a circle (helix) to a series of points was solved in the absence of multiple scattering - by
 - V. Karimäki CMS Note 1997/064 [NIM A410 (1998) 284] & NIM A305 (1991) 187
 - used for track fitting with UA1 wire chambers where MS is minor effect

$$\varepsilon_i \approx \frac{1}{2}\rho r_i^2 - (1+\rho d)r_i \sin(\phi - \phi_i) + \frac{1}{2}\rho d^2 + d$$

 ρ = curvature = ±1/R where R is radius of curvature

- ϕ = direction of propagation at point of closest approach
- d = distance of closest approach to the origin
- general prescription for estimating MS effect is to add spatial errors in quadrature

Errors from Karimäki calculation

• Covariance matrix: W and its inverse – when no correlations present -

• Solved explicitly to good approximation

$$\begin{cases} \sigma_{\rho\rho} = C \left[4\sigma_{xx} - 4\rho^2 \left(\left\langle x^2 \right\rangle^2 - \left\langle x \right\rangle \left\langle xr^2 \right\rangle + \frac{1}{4}\rho^2 \left\langle xr^2 \right\rangle^2 \right) \right] \\ \sigma_{\rho\phi} = C \left[2\sigma_{xr^2} - \rho^2 \left(2 \left\langle x^2 \right\rangle \left\langle xr^2 \right\rangle - \left\langle r^2 \right\rangle \left\langle xr^2 \right\rangle - \left\langle x \right\rangle \left\langle r^4 \right\rangle + \frac{1}{2}\rho^2 \left\langle r^4 \right\rangle \left\langle xr^2 \right\rangle \right) \right] \\ \sigma_{\phi\phi} = C \left[\sigma_{r^2r^2} + \rho^2 \left\langle r^4 \right\rangle \left(\left\langle y^2 \right\rangle - \frac{1}{4}\rho^2 \left\langle r^4 \right\rangle \right) \right] \\ \sigma_{\rho d} = C \left[2 \left\langle x \right\rangle \left\langle xr^2 \right\rangle - 2 \left\langle x^2 \right\rangle \left\langle r^2 \right\rangle - \rho^2 \left(\left\langle xr^2 \right\rangle^2 - \left\langle x^2 \right\rangle \left\langle r^4 \right\rangle \right) \right] \\ \sigma_{\phi d} = C \left[\left\langle x \right\rangle \left\langle r^4 \right\rangle - \left\langle r^2 \right\rangle \left\langle xr^2 \right\rangle \right] \\ \sigma_{dd} = C \left[\left\langle x^2 \right\rangle \left\langle r^4 \right\rangle - \left\langle xr^2 \right\rangle^2 \right] \end{cases}$$

$$\sigma_{ab} = \langle ab \rangle - \langle a \rangle \langle b \rangle$$
 $\langle u \rangle = \sum w_i u_i / \sum w_i$ see papers for details



he track angle of incidence.² The resolution degrades with increasing fluence and biause of the reduced charge sharing.

igure 6.6: Strip tracker cluster position r

Measurement error

Track width (strips

Material in present system



Pixels only

Simplified model

- Present system: 3 pixel + 10 outer strip
- Each pixel layer assumed identical
 - − $t_{eff} \approx 1.6$ mm Si equivalent => $t_{eff}/X_0 \approx 0.017$ per layer
 - Total $t_{eff}/X_0 \approx 0.051$ @ $\eta = 0$
- Outer tracker: two types of layer
 - − $t_{eff} \approx 2.4$ mm Si equivalent (single) => $t_{eff}/X_0 \approx 0.026$ per layer
 - − $t_{eff} \approx 4.84$ mm Si equivalent (stereo) => $t_{eff}/X_0 \approx 0.051$ per layer
 - Total $t_{eff}/X_0 \approx 0.359$ @ $\eta = 0$
- Beam pipe
 - 800µm Be beam pipe => $t_{eff}/X_0 \approx 0.0027$
 - only affects projection back to primary vertex

Errors assigned for fitting direction

Combination of measurement + multiple scatter at earlier plane • $\theta_0 = \frac{13.6MeV}{\beta cp} z \sqrt{x/X_0} \left[1 + 0.038 \ln(x/X_0) \right]$

_	multiple	scattering	dominates
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p = 1 GeV/ci R t_{eff} X_0 t_{eff}/X_0 σ_{meas} $\sigma(\theta_{MS})$ σ_{i} [cm] [cm] [cm] [µm] [µm] mrad 2.9 Be 0.08 35.28 0.0023 0.50 1 2 4.4 Si 0.16 0.017 9.36 10 1.53 12 7.3 Si 0.16 0.017 3 9.36 1.53 51 10 Si 10.2 0.16 0.017 4 9.36 10 1.53 102 25.5 Si 0.46 0.051 5 9.36 2.72 24 501 0.46 0.051 34.7 Si 9.36 2.72 6 24 789 Si 0.23 0.025 1.89 1143 7 43.9 9.36 36 •• •• •• •• •• •• 14 108.3 Si 0.23 0.026 36 9.36 2.15 7073

small corrections for incident angle

$$t_{eff} = t_{layer}/cos(\alpha)$$

Note growth of σ with R

Elba TK week May 2010

Example results from **full** simulation

From CMS detector paper & Physics TDR

Transverse impact parameter



Momentum resolution

Results at $\eta = 0$



Correlations from multiple scattering



- $C_{11} = \langle y_1 y_1 \rangle = \sigma_1^2$ $\sigma_1 = intrinsic measurement error$
- $C_{22} = \langle y_2 y_2 \rangle = \langle x_{21} \theta_1 x_{21} \theta_1 \rangle = x_{21}^2 \langle \theta_1^2 \rangle$ (+ σ_2^2 if not negligible, etc)
- $C_{33} = \langle y_3 y_3 \rangle = \langle (x_{31} \theta_1 + x_{32} \theta_2) (x_{31} \theta_1 + x_{32} \theta_2) \rangle = x_{31}^2 \langle \theta_1^2 \rangle + x_{32}^2 \langle \theta_2^2 \rangle$
- $C_{21} = \langle y_2 y_1 \rangle = 0$
- $C_{23} = \langle y_2 y_3 \rangle = \langle x_{21} \theta_1 (x_{31} \theta_1 + x_{32} \theta_2) \rangle = x_{21} x_{31} \langle \theta_1^2 \rangle$ etc
- Does inclusion of off-diagonal terms affect result?

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Simple example

- 3 equally spaced, identical planes, $\Delta x = \delta$, multiple scattering dominates
- Straight line case. Minimise $\chi^2 = \sum \varepsilon_i C_{ij}^{-1} \varepsilon_j$ $x_1 = 0, x_2 = \delta, x_3 = 2\delta$

Covariance matrix C =
$$\begin{bmatrix} \sigma_1^2 & C_{12} & C_{13} \\ C_{12} & \sigma_2^2 & C_{23} \\ C_{13} & C_{23} & \sigma_3^2 \end{bmatrix} \quad \sigma^2(\theta) = \sum_{i,j} \frac{\partial \theta}{\partial y_i} C_{ij}^{-1} \frac{\partial \theta}{\partial y_j} = \frac{1}{\sum x_i x_j C_{ij}^{-1}}$$

• without correlations: C & C⁻¹

$$\begin{bmatrix} \sigma_{1}^{2} & 0 & 0 \\ 0 & \delta^{2} \langle \theta^{2} \rangle & 0 \\ 0 & 0 & 5\delta^{2} \langle \theta^{2} \rangle \end{bmatrix} \begin{bmatrix} \frac{1}{\sigma_{1}^{2}} & 0 & 0 \\ 0 & \frac{1}{\delta^{2} \langle \theta^{2} \rangle} & 0 \\ 0 & \frac{1}{\delta^{2} \langle \theta^{2} \rangle} & 0 \\ 0 & 0 & \frac{1}{5\delta^{2} \langle \theta^{2} \rangle} \end{bmatrix} \begin{bmatrix} \sigma^{2} & 0 & 0 \\ 0 & \delta^{2} \langle \theta^{2} \rangle & 2\delta^{2} \langle \theta^{2} \rangle \\ 0 & 2\delta^{2} \langle \theta^{2} \rangle & 5\delta^{2} \langle \theta^{2} \rangle \end{bmatrix} \begin{bmatrix} \frac{1}{\sigma_{1}^{2}} & 0 & 0 \\ 0 & \frac{5}{\delta^{2} \langle \theta^{2} \rangle} & \frac{-2}{\delta^{2} \langle \theta^{2} \rangle} \\ 0 & 0 & \frac{1}{5\delta^{2} \langle \theta^{2} \rangle} \end{bmatrix} \begin{bmatrix} \sigma^{2} & 0 & 0 \\ 0 & \frac{-2}{\delta^{2} \langle \theta^{2} \rangle} & \frac{1}{\delta^{2} \langle \theta^{2} \rangle} \\ 0 & \frac{-2}{\delta^{2} \langle \theta^{2} \rangle} & \frac{1}{\delta^{2} \langle \theta^{2} \rangle} \end{bmatrix}$$

at least proves that correlations can't be ignored

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Errors with correlation terms

• To calculate covariance matrix W and inverse in full, replace

$$W_{kl} = \sum_{i} w_{i} \frac{\partial \varepsilon_{i}}{\partial \alpha_{k}} \frac{\partial \varepsilon_{i}}{\partial \alpha_{l}} \quad \text{with} \quad W_{kl} = \sum_{i,j} \frac{\partial \varepsilon_{i}}{\partial \alpha_{k}} C_{ij}^{-1} \frac{\partial \varepsilon_{j}}{\partial \alpha_{l}}$$

Terms needed already provided by Karimäki:

$$\frac{\partial \varepsilon_i}{\partial \rho} = \frac{1}{2} r_i^2 \qquad \qquad \frac{\partial \varepsilon_i}{\partial \phi} = -x_i \qquad \qquad \frac{\partial \varepsilon_i}{\partial d} = 1 + \rho y_i$$

• The solutions are the diagonal terms of W⁻¹

$$\sigma^{2}(\rho) = W_{11}^{-1} \qquad \sigma^{2}(\phi) = W_{22}^{-1} \qquad \sigma^{2}(d) = W_{33}^{-1}$$

- with the origin chosen to be on the beam line
 - The beam pipe is a dummy measurement plane to correctly include its offdiagonal contributions
 - This changed some of the results I have shown previously

Results from calculation



Results from calculation (ii)

Added numerical interpolation of material for $\eta > 0$



Results from calculation (iii)

Angular resolution also calculated

NB small but noticeable sensitivity at low p to changes in pixel point resolution in layer 1, eg 10->15μm

However, this is at the limit of the achievable precision in the modelling (even in full simulation)



Scale view of Tracker



Impact error from pixels alone



Physics TDR Vol 1

Figure 6.17: Transverse momentum (left) and transverse impact parameter (right) resolution for single muon tracks, created directly from hit triplets.

Present pixel stand alone

- Quite good agreement in both IP and momentum resolution
 - Proper matrix treatment removes discrepancy I thought due to hit merging



Preview of future

- Some indication of benefits of 4 layer system
 - reduced radii: 2.5 cm beam pipe, pixels: 3.9, 6.8, 10.9, 16.0 cm
 - pixel material reduced by factor 2.7 compared to present system



Effect of shrinking radially?

- All layers move in or out by fixed amount
- If material reduction is as expected, then further benefits from reducing radial dimensions appear to be limited



Use of b-layer



Stand alone pixels





Smaller pixels?

- Assume r-φ resolution scales with pixel size
 - also indicates effect of degradation due to radiation damage
 - scope for further detailed evaluation if useful



Conclusions

- Full covariance matrix calculation of errors gives good insight into possible layout variations
 - basically, emulates real life or full Monte Carlo
 - essential where multiple scattering errors are important
 - allows very fast comparison between different options, including adding/ removing layers, changing material, etc
 - calculations can play a role in optimising and exploring tracker designs
 - can be added to Layout Tool for many more details to be evaluated
- Material degrades performance (you will be surprised to learn!)
 - in pixels degrades mainly impact parameter
 - in outer tracker affects mainly momentum resolution
 - innermost radial point is most important
- Many more interesting cases can be studied
 - and complements full simulations (of fewer options)

For reference: Covariance matrix W

$$\begin{split} W_{kl} &= \sum_{i,j} \frac{\partial \varepsilon_i}{\partial \alpha_k} C_{ij}^{-1} \frac{\partial \varepsilon_j}{\partial \alpha_l} \\ &= \frac{\partial \varepsilon_i}{\partial \rho} = \frac{1}{2} r_i^2 \qquad \qquad \frac{\partial \varepsilon_i}{\partial \phi} = -x_i \qquad \qquad \frac{\partial \varepsilon_i}{\partial d} = 1 + \rho y_i \\ W_{11} &= \sum_{i,j} \frac{1}{4} r_i^2 r_j^2 C_{ij}^{-1} \qquad W_{22} = \sum_{i,j} x_i x_j C_{ij}^{-1} \qquad W_{33} = \sum_{i,j} (1 + \rho y_i)(1 + \rho y_j) C_{ij}^{-1} \\ W_{12} &= \sum_{i,j} -\frac{1}{2} r_i^2 x_j C_{ij}^{-1} \qquad W_{13} = \sum_{i,j} \frac{1}{2} r_i^2 (1 + \rho y_j) C_{ij}^{-1} \qquad W_{23} = \sum_{i,j} -x_i (1 + \rho y_j) C_{ij}^{-1} \\ \sigma^2(\rho) &= W_{11}^{-1} \qquad \sigma^2(\phi) = W_{22}^{-1} \qquad \sigma^2(d) = W_{33}^{-1} \end{split}$$

Impact error from full simulation

From CMS detector paper & Physics TDR v1

Angular resolution

Longitudinal impact error

